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Electrical equipment for measurement, control and laboratory use - EMC requirements -
Part 2-7: Particular requirements - Test configurations, operational conditions, test levels and performance criteria for devices with Ethernet-APL interfaces

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

Electrical equipment for measurement, control and laboratory use - EMC requirements - Part 2-7: Particular requirements - Test configurations, operational conditions, test levels and performance criteria for devices with Ethernet-APL interfaces

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Draft	Report on voting
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This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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